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THIS SPEC IS OBSOLETE

Spec No: 38-05475

Spec Title: CY7C1049DV33, 4-MBIT (512K X 8) STATIC

RAM

Replaced by: None



4-Mbit (512K × 8) Static RAM

Features

- Pin and function compatible with CY7C1049CV33
- High speed
 □ t_{AA} = 10 ns
- Low active power
 □ I_{CC} = 90 mA at 10 ns
- Low CMOS standby power
 □ I_{SB2} = 10 mA
- 2.0 V data retention
- Automatic power down when deselected
- TTL compatible inputs and outputs
- Easy memory expansion with CE and OE features
- Available in Pb-free 36-pin (400 Mil) molded SOJ and 44-pin TSOP II packages

Functional Description

The CY7C1049DV33 is a high performance CMOS Static RAM organized as 512K words by 8-bits. Easy memory expansion is provided by an Active LOW Chip Enable ($\overline{\text{CE}}$), an Active LOW Output Enable ($\overline{\text{OE}}$), and tristate drivers. You can write to the device by taking Chip Enable ($\overline{\text{CE}}$) and Write Enable ($\overline{\text{WE}}$) inputs LOW. Data on the eight I/O pins (IO₀ through IO₇) is then written into the location specified on the address pins (A₀ through A₁₈).

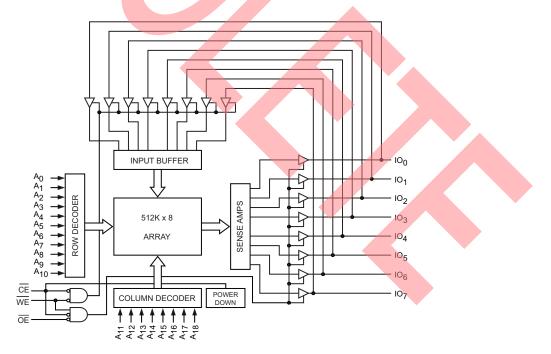
You can read from the device by taking Chip Enable (\overline{CE}) and Output Enable (\overline{OE}) LOW while forcing Write Enable (\overline{WE}) HIGH. Under these conditions, the contents of the memory location specified by the address pins appear on the I/O pins.

The eight input or output pins (IO₀ through IO₇) are <u>placed</u> in a high impedance state whe<u>n</u> the device is deselected (CE HIGH), the outputs are <u>disabled</u> (OE HIGH), or during a write operation (CE LOW, and WE LOW).

The CY7C1049DV33 is available in standard 400 Mil wide 36-pin SOJ package and 44-pin TSOP II package with center power and ground (revolutionary) pinout.

For a complete list of related documentation, click here.

Logic Block Diagram





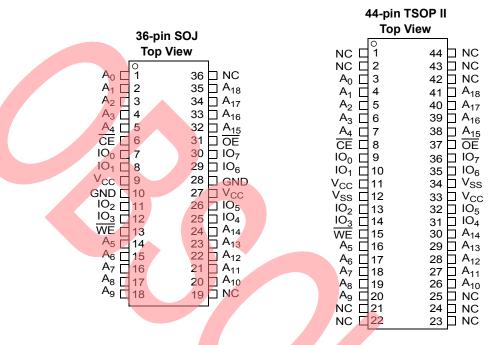
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Pin Configuration



Selection Guide

Description		-10 (I	ndustrial)	Unit	
Maximum access time			10		ns	
Maximum operating current			90		mA	
Maximum CMOS standby current			10		mA	



Maximum Ratings

Exceeding the maximum ratings may impair the useful life of the device. User guidelines are not tested.

Storage temperature—65 °C to +150 °C Ambient temperature with Supply voltage on V_{CC} to relative GND^[1]–0.3 V to +4.6 V

DC input voltage ^[1] Current into outputs (LOW)	
Static discharge voltage	
(MIL-STD-883, Method 3015)	
Latch up current	> 200 mA
Operating Pange	

Operating Range

Range	Ambient Temperature	V _{cc}	Speed
Industrial	–40 °C to +85 °C	$3.3~V\pm0.3~V$	10 ns

Electrical Characteristics

Over the Operating Range

			-10 (Inc	lustrial)	
Parameter	Description	Test Conditions	Min	Max	Unit
V _{OH}	Output HIGH voltage	V _{CC} = Min, I _{OH} = -4.0 mA	2.4	_	V
V _{OL}	Output LOW voltage	V _{CC} = Min, I _{OL} = 8.0 mA	_	0.4	V
V _{IH} ^[1]	Input HIGH voltage		2.0	V _{CC} + 0.3	V
V _{IL} [1]	Input LOW voltage ^[1]		-0.3	0.8	V
I _{IX}	Input leakage current	$GND \le V_I \le V_{CC}$	-1	+1	μА
I _{OZ}	Output leakage current	GND ≤ V _{OUT} ≤ V _{CC} , Output Disabled	-1	+1	μΑ
I _{CC}	V _{CC} operating supply current	V _{CC} = Max, 100 MHz	_	90	mA
		$f = f_{MAX} = 1/t_{RC}$	_	80	mA
		66 MHz	-	70	mA
		40 MHz	-	60	mA
I _{SB1}	Automatic CE Power down current —TTL Inputs		-	20	mA
I _{SB2}	Automatic CE Power down current —CMOS Inputs	$\begin{aligned} &\text{Max V}_{\text{CC}}, \overline{\text{CE}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \\ &\text{V}_{\text{IN}} \geq \text{V}_{\text{CC}} - 0.3 \text{ V}, \text{ or V}_{\text{IN}} \leq 0.3 \text{ V}, \\ &\text{f} = 0 \end{aligned}$	-	10	mA

Capacitance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions		Max	Unit
C _{IN}	Input capacitance	$T_A = 25 ^{\circ}\text{C}, f = 1 \text{MHz}, V_{CC} = 3.3 \text{V}$		8	pF
C _{OUT}	I/O capacitance			8	pF

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^{1.} V_{IL} (min.) = -2.0 V and V_{IH} (max) = V_{CC} + 2 V for pulse durations of less than 20 ns.



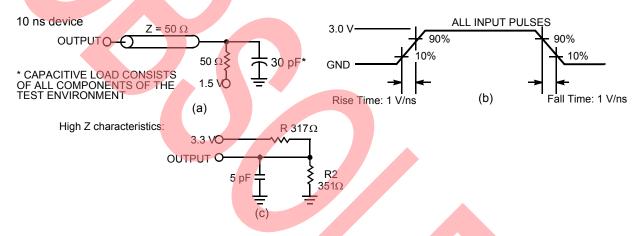
Thermal Resistance

Tested initially and after any design or process changes that may affect these parameters.

Parameter	Description	Test Conditions	36-pin SOJ Package	44-pin TSOP II Package	Unit
Θ_{JA}	Thermal resistance (Junction to Ambient)	Still Air, soldered on a 3 × 4.5 inch, two layer printed circuit board	57.91	50.66	°C/W
Θ _{JC}	Thermal resistance (Junction to Case)		36.73	17.17	°C/W

AC Test Loads and Waveforms

Figure 1. AC Test Loads and Waveforms [4]



Data Retention Characteristics

Over the Operating Range

Parameter	Description	Conditions [4]	Min	Max	Unit
V_{DR}	V _{CC} for data retention		2.0	-	V
ICCDR	Data retention current	$V_{CC} = V_{DR} = 2.0 \text{ V}, \overline{CE} \ge V_{CC} - 0.3 \text{ V}$ $V_{IN} \ge V_{CC} - 0.3 \text{ V} \text{ or } V_{IN} \le 0.3 \text{ V}$	-	10	mA
t _{CDR} ^[2]	Chip deselect to data retention time		0	-	ns
t _R ^[5]	Operation recovery time		t _{RC}	-	ns

Figure 2. Data Retention Waveform



Notes

- 2. Tested initially and after any design or process changes that may affect these parameters.
- AC characteristics (except High Z) are tested using the load conditions shown in Figure 1 (a). High Z characteristics are tested for all speeds using the test load shown in Figure 1 (c).
- No input may exceed V_{CC} + 0.3 V.
- 5. Full device operation requires linear V_{CC} ramp from V_{DR} to $V_{CC(min.)} \ge 50 \,\mu s$ or stable at $V_{CC(min.)} \ge 50 \,\mu s$.

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AC Switching Characteristics

Over the Operating Range [6]

		-10 (Inc	dustrial)	
Parameter	Description	Min	Max	Unit
Read Cycle			•	
t _{power} ^[7]	V _{CC} (typical) to the first access	100	_	μS
t _{RC}	Read cycle time	10	_	ns
t _{AA}	Address to data valid	_	10	ns
t _{OHA}	Data hold from address change	3	-	ns
t _{ACE}	CE LOW to data valid	_	10	ns
t _{DOE}	OE LOW to data valid	_	5	ns
t _{LZOE}	OE LOW to Low Z ^[8]	0	_	ns
t _{HZOE}	OE HIGH to High Z ^[8, 9]	_	5	ns
t _{LZCE}	CE LOW to Low Z ^[8]	3	_	ns
t _{HZCE}	CE HIGH to High Z ^[8, 9]	_	5	ns
t _{PU}	CE LOW to power up	0	_	ns
t _{PD}	CE HIGH to power down	_	10	ns
Write Cycle ^[10, 1]				
t _{WC}	Write cycle time	10	-	ns
t _{SCE}	CE LOW to write end	7	_	ns
t _{AW}	Address setup to write end	7	_	ns
t _{HA}	Address hold from write end	0	_	ns
t _{SA}	Address setup to write start	0	_	ns
t _{PWE}	WE pulse width	7	_	ns
t _{SD}	Data setup to write end	5	-	ns
t _{HD}	Data hold from write end	0	-	ns
t _{LZWE}	WE HIGH to Low Z ^[8]	3	-	ns
t _{HZWE}	WE LOW to High Z ^[8, 9]	-/_/	5	ns

Notes

- Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5 V, input pulse levels of 0 to 3.0 V, and output loading of the specified I_{OL}/I_{OH} and 30 pF load capacitance.

- and 30 pF load capacitance.

 1. t_{POWER} gives the minimum amount of time that the power supply must be at stable, typical V_{CC} values until the first memory access is performed.

 2. t_{POWER} gives the minimum amount of time that the power supply must be at stable, typical V_{CC} values until the first memory access is performed.

 3. At any temperature and voltage condition, t_{HZCE} is less than t_{LZOE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} for any given device.

 4. t_{HZOE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in part (c) of Figure 1 on page 5. Transition is measured when the outputs enter a high impedance state.

 4. The internal write time of the memory is defined by the overlap of CE LOW, and WE LOW. CE and WE must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set up and hold timing must be referred to the leading edge of the signal that terminates the write.

 11. The minimum write cycle time for Write Cycle No. 2 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.



Switching Waveforms

Figure 3. Read Cycle No. 1^[12, 13]

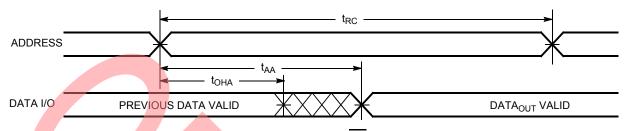


Figure 4. Read Cycle No. 2 (OE Controlled)[13, 14]

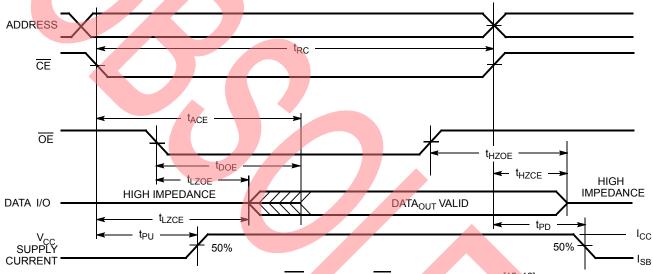
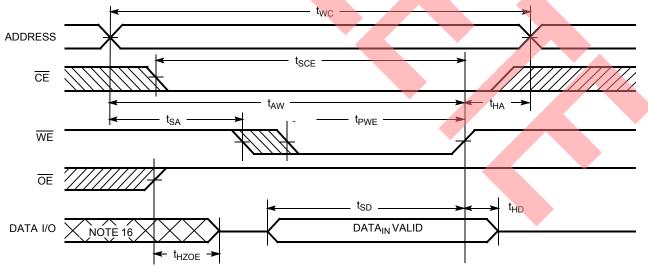


Figure 5. Write Cycle No. 1 (WE Controlled, OE HIGH During Write)[15, 16]



Notes

- 12. <u>Dev</u>ice is continuously selected. OE, CE = V_{IL}.

 13. WE is HIGH for read cycle.

 14. Address valid prior to or coincident with CE transition LOW.

 15. <u>Data</u> I/O is high impedance if OE = V_{IH}.

 16. If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



Switching Waveforms (continued)

Figure 6. Write Cycle No. 2 ($\overline{\text{WE}}$ Controlled, $\overline{\text{OE}}$ LOW)^[17]

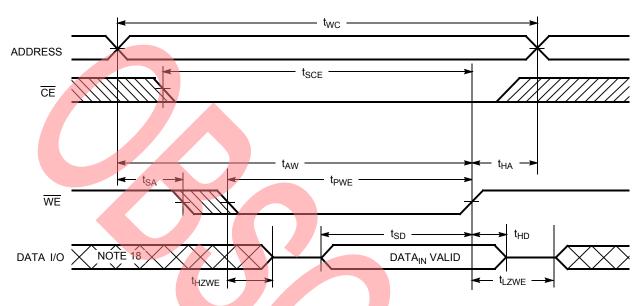
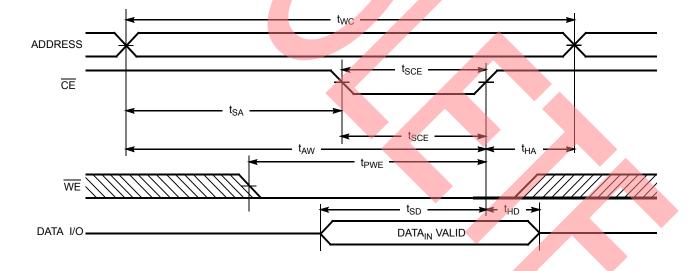


Figure 7. Write Cycle No. 3 (CE Controlled)[17, 19]



^{17.} If CE goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.

18. During this period the I/Os are in the output state and input signals must not be applied.

19. Data I/O is high impedance if OE = V_{IH}.



Truth Table

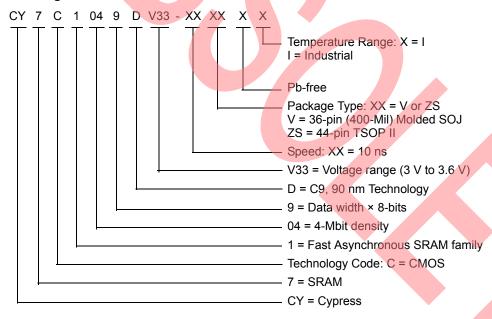
CE	OE	WE	IO ₀ –IO ₇	Mode	Power
Н	Х	Х	High Z	Power down	Standby (I _{SB})
L	L	Н	Data Out	Read	Active (I _{CC})
L	Х		Data In	Write	Active (I _{CC})
L	Н	Н	High Z	Selected, Outputs Disabled	Active (I _{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
10	CY7C1049DV33-10VXI	51-85090	36-pin (400-Mil) Molded SOJ (Pb-free)	Industrial
	CY7C1049DV33-10ZSXI	51-85087	44-pin TSOP II (Pb-free)	

Contact your local Cypress sales representative for availability of these parts.

Ordering Code Definitions

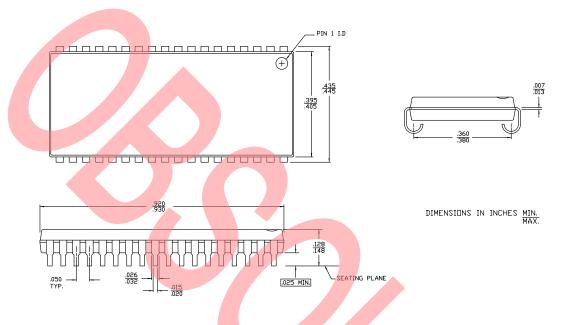




Package Diagrams

Figure 8. 36-pin (400-Mil) Molded SOJ V36.4, (51-85090)

36 Lead (400 MIL) Molded SOJ V36



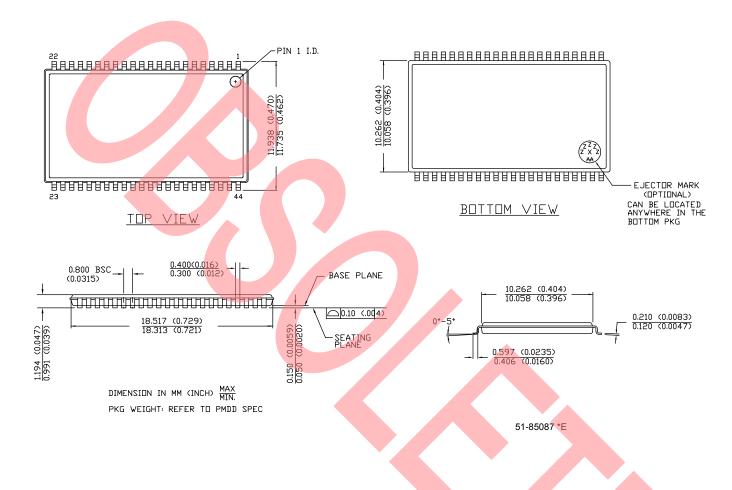
51-85090 *F



Package Diagrams (continued)

Figure 9. 44-pin TSOP Z44-II, (51-85087)

44 Lead TSOP TYPE II - STANDARD





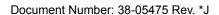
Acronyms

Acronym	Description			
CE	chip enable			
CMOS	complementary metal oxide semiconductor			
I/O	input/output			
ŌĒ	output enable			
SOJ	small outline J-lead			
SRAM	static random access memory			
TSOP	thin small outline package			
TTL	transistor-transistor logic			
WE	write enable			

Document Conventions

Units of Measure

Symbol	Unit of Measure			
°C	degree Celcius			
MHz	megahertz			
μΑ	microamperes			
μs	microseconds			
mA	milliamperes			
mm	millimeter			
ms	milliseconds			
ns	nanoseconds			
Ω	ohms			
%	percent			
pF	pico Farad			
V	Volts			
W	Watts			





Document History Page

	t Number: 3		,	K × 8) Static RAM
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change
**	201560	See ECN	SWI	Advance Datasheet for C9 IPP
*A	233729	See ECN	SYT	1.AC, DC parameters are modified as per EROS (Specification # 01-2165) 2.Pb-free offering in the Ordering Information Table
*B	351096	See ECN	PCI	Changed status from Advance to Preliminary. Removed 20 ns Speed bin Corrected DC voltage (min) value in maximum ratings section from - 0.5 to - 0.3 Redefined I _{CC} values for Com'l and Ind'l temperature ranges I _{CC} (Com'l): Changed from 100, 80, and 67 mA to 90, 80 and, 75 mA for 8, 10, and 12ns speed bins respectively I _{CC} (Ind'l): Changed from 80 and 67 mA to 90 and 85 mA for 10 and 12ns speed bins respectively Added V _{IH(max}) specification in Note# 2 Changed reference voltage level for measurement of High Z parameters from ±50 mV to ±200 mV Added Data Retention Characteristics, Waveform, and footnotes 11 and 12 Changed Package Diagram name from 44-pin TSOP II Z44 to 44-pin TSOP II Z54 Changed part names from Z to ZS in the Ordering Information Table Added Pb-free Ordering Information Table Shaded Ordering Information Table
*C	446328	See ECN	NXR	Changed status from Preliminary to Final. Removed -8 speed bin Removed Commercial Operating Range product information Added Automotive Operating Range product information Updated Thermal Resistance table Updated footnote #8 on High Z parameter measurement Replaced Package Name column with Package Diagram in the Ordering Information table
*D	1274726	See ECN	VKN/AESA	Updated Pin Configuration. Corrected typo in the 44-pin TSOP II pinout.
*E	2899972	03/29/2010	AJU	Updated Package Diagrams.
*F	3059162	10/14/2010	PRAS	Added Ordering Code Definitions. Updated Package Diagrams.
*G	3266084	05/28/2011	PRAS	Updated Functional Description (Removed "Refer to the Cypress application no AN1064, SRAM System Guidelines for best practice recommendations."). Added Acronyms and Units of Measure. Updated to new template.
*H	3440302	11/16/2011	TAVA	Removed Automotive Temperature Range related information in all instances across the document. Updated Switching Waveforms. Updated Ordering Information: Updated part numbers.
*	4574311	11/19/2014	TAVA	Updated Functional Description: Added "For a complete list of related documentation, click here." at the end. Updated Package Diagrams: spec 51-85090 – Changed revision from *E to *F.
*J	5544150	12/06/2016	VINI	Obsolete document. Completing Sunset Review.



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